Dynam ical mean eld theory for strongly correlated inhom ogeneous multilayered nanostructures

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D ynam ical mean eld theory is employed to calculate the properties of multilayered inhom ogeneous devices composed of sem i-in nite metallic lead layers coupled via barrier planes that are made from a strongly correlated material (and can be tuned through the metal-insulator M ott transition). We nd that the Friedel oscillations in the metallic leads are immediately frozen in and don't change as the thickness of the barrier increases from one to eighty planes. We also identify a generalization of the T houless energy that describes the crossover from tunneling to incoherent 0 hm ic transport in the insulating barrier. We qualitatively compare the results of these self-consistent many-body calculations with the assumptions of non-self-consistent Landauer-based approaches to shed light on when such approaches are likely to yield good results for the transport.

PACS num bers: 71.30.+ h, 73.40.Rw, 73.20.-r, 73.40.-c

I. IN TRODUCTION

The elds of strongly correlated m aterials and of nanotechnology are being united by work that investigates what happens when correlated m aterials are placed into inhom ogeneous environm ents on the nanoscale. This can be accomplished by carefulgrow th of strongly correlated m aterials with m olecular beam epitaxy or pulsed laser deposition, or it may be an intrinsic property of som e strongly correlated system s that display either nanoscale phase separation, or nanoscale inhom ogeneity. There are fundam ental questions about these systems | what happens to the properties of the system when it has inhom ogeneities on the nanoscale and how does this spatial connem ent m odify the quantum -m echanical correlations?

W e investigate a special case of a correlated nanostructure, where we can carefully control the quantum con nement e ects. W e take a sem i-in nite ballistic-metal lead and couple it to another sem i-in nite ballistic-m etal lead via a strongly correlated barrier m aterial (which is from one to eighty atom ic planes thick). A sthe barrier is made thinner, the strongly correlated system is being con ned in one spatial direction between the metallic leads. But the metallic leads induce a proximity e ect on the barrier, which can decon ne the correlated system . Indeed, we will see that system s with a single-plane barrier still display upper and low erM ott bands, but they also have a low -energy low -w eight peak to the density of states that arises from the proximity-e ect induced states that are localized near the interfaces of the leads and the barrier. As the barrier is made thicker, this peak becomes a dip, which decreases exponentially with the thickness.

We employ dynamical mean eld theory (DMFT) in this work. This allows us to self-consistently calculate the properties of the inhom ogeneous system, including Friedel-like oscillations in the leads, and the proxim itye ect on the barrier. We do not need to make any assumptions about the kind of transport through this device, be it ballistic, di usive, tunneling, or incoherent (via therm al excitations), since the DMFT automatically incorporates all kinds of transport within its form alism¹. We are, however, making one approxim ation in this approach | namely, we make the assumption that the self energy remains local, even though it can vary from plane to plane in the multilayered nanostructure. Such an approximation should work ne for these inhom ogeneous system s, since the coordination number remains the same throughout the device (and we are working in three dimensions). This is to be contrasted with more conventional approaches to tunneling, which assume a single-particle approach and employ a phenom enological potential to describe the barrier region². The wavefunctions, transmission, and re ection coe cients can be calculated, and then the transport analyzed, as in a Landauer-based approach. In the DMFT calculations, we determ ine the potential self-consistently (i.e., the self energy) from the m icroscopic param eters of the H am iltonian, and the potential can vary with the energy of the scattering states. It is not clear that a sim ple phenom enological potential can reproduce the sam e kind of behavior via a conventional tunneling approach.

We assume each of the multilayer planes has translational invariance in the perpendicular x-and y-directions. This allows us to use a mixed basis, Fourier transform - ing the two perpendicular directions to k_x and k_y , but keeping the z-direction in real space. Then for each two-dimensional band energy, we have a quasi one dimensional problem to solve, which has a tridiagonal representation in real space, and can be solved with a renorm alized perturbation expansion³. It is this mixed-basis representation (introduced by Pottho and Nolting¹) that allows us to solve this problem. By iterating our many-body equations, we can achieve a self-consistent solution.

In addition to single-particle properties, we also evaluate z-axis transport, perpendicular to the multilayers. Thouless introduce the idea of using the dw elltim ew ithin the barrier to de ne a quantum energy scale $\sim = t_{dw \, ell}$, which turned out to describe the dynam ics and transport of both ballistic m etal and di usive m etal barriers^{4,5}. The concept has been applied widely to the quasiclas-

sical theory of Josephson junctions as well⁶. If we don't focus on the time spent within the barrier, but instead try to extract an energy scale from the resistance of a device, then we can generalize the Thouless energy to the case of an insulating barrier, where the transport arises from either tunneling or incoherent (therm ally activated) processes. We nd that when this energy scale is on the order of the tem perature, then we have a crossover from tunneling to incoherent transport. A short communication of this work has already appeared⁷.

The organization of this paper is as follows: in Section II, we present a detailed derivation of the form alism and the num erical algorithm s used to calculate properties of nanostructures. In Section III, we describe the single-particle properties, focusing on the density of states and the self energy. In Section IV, we generalize the concept of the Thouless energy, which is applied to charge transport in Section V.W e end with our conclusions in Section V I.

II. FORM ALISM AND NUMERICAL ALGORITHMS

The Ham iltonian we consider involves a hopping term for the electrons and an interaction term for the sites within the barrier region (interactions can be added in the metal if desired to convert the leads from a ballistic metal to a di usive metal, but we do not do so here). For the interaction, we employ the Falicov-K in ball model[®] which involves an interaction between the conduction electrons with localized particles (thought of as f-electrons or charged ions) when the conduction electron hops onto a site occupied by the localized particle. We consider spinless electrons here, but spin can be included trivially by introducing a factor of 2 into som e of the results. The Ham iltonian is

where t_{ij} is a Hermitian hopping matrix, U_i is the Falicov-K im ball interaction, and wi is a classical variable that equals one if there is a localized particle at site i and zero if there is no localized particle at site i (a chem ical potential is employed to adjust the conduction-electron concentration). Since we are considering multilayered heterostructures, we assume that the hopping matrix is translationally invariant within each plane, as well as the Falicov-K im ball interaction. W e let the z-direction denote the direction where the system is allowed to have inhom ogeneity. Then our translational invariance in the parameters requires that $U_i = U_j$ if $R_i = R_j$ has a vanishing z-component. Similarly, $t_{ij} = t_{i^0j^0}$ if $R_i = R_{i^0}$ and R j R j⁰ both have a vanishing z-component, and $R_i = R_{i^0} = R_{i^0}$. But this requirement is quite modest, and allows for many complex situations to be considered.

We denote the planes with a given z-component by a G reek label (, , , ...). Then our requirement on the interaction is that U has a denite value for each plane . The hopping matrix can have one value t^k for the hopping within the plane, and di erent values t ; +1 and t 1; for hopping to the plane to the right and for hopping to the plane to the left, respectively. For sim plicity, we will only consider nearest-neighbor hopping here, and we assume the lattice positions R_i all lie on the points of a sim ple cubic lattice (but we do not have full cubic symmetry).

Because of the translational invariance within each plane, we can perform a Fourier transform in the x- and y-coordinates to the mixed basis k_x , k_y , and (the z-com ponent in realspace). We denot the two-dimensional band structure, for each plane , by

$$^{2d}(k_x;k_y) = 2t^k[\cos k_x + \cos k_y]:$$
 (2)

The Green's function, in real space, is de ned by

$$G_{ij}() = hT C_i()C_j^V(0)i;$$
 (3)

for imaginary time . The notation ho i denotes the N])O divided by the partition trace Trexp ([H function Z = Trexp([H N]) and the operators are expressed in the Heisenberg representation O() = N]). The symbol T exp(H N])0 exp([H denotes time ordering of operators, with earlier values appearing to the right and is the inverse tem perature (= 1=T). W e will work with the M atsubara frequency G reen's functions, de ned for in aginary frequencies $i!_n = i T (2n + 1)$. The Green's function at each M atsubara frequency is determined by a Fourier transform at ion

$$G_{ij}(i!_n) = \int_{0}^{Z} d e^{i!_n} G_{ij}():$$
 (4)

W e also will work with the analytic continuation of the tim e-ordered G reen's functions to the realaxis (retarded or advanced G reen's functions), with $i!_n ! ! i0^+$. W e use the symbol Z to denote a general variable in the complex plane (although we will mainly be interested in either Z = $i!_n$ or Z = $! + i0^+$). Finally, we work in the m ixed basis described above, where we Fourier transform the x- and y-components to m om entum space, to give G (k;Z), where R_i has a z-component equal to and R_j has a z-component equal to (k is a two-dimensional wavevector).

W ith all of this notation worked out, we can write the equation of motion for the G reen's function in real space¹, which satis es

$$G_{ij}^{1}(Z) = (Z +)_{ij} _{ij} (Z)_{ij} + t_{ij}$$
 (5)

Now we go to a mixed-basis, by Fourier transforming in the x- and y-directions to nd

$$G^{1}(k;Z) = [Z + (Z)^{2d}(k)] + t_{+1} + t_{1} + t_{1} ; (6)$$

with (Z) the local self energy for plane . Finally, we use the identity G (Z) G^{1} (Z) = to get the starting point for the recursive solution to the problem :

$$= G (k;Z)[Z + (Z) 2d(k)] + G _1(k;Z)t _1 + G _{+1}(k;Z)t_{+1} : (7)$$

The equation of motion in Eq. (7) has a tridiagonal form with respect to the spatial component z, and hence it can be solved by employing the renormalized perturbation expansion³. We illustrate the solution exactly here. The equation with = is di erent from the equations with ϵ . The form er is solved directly via

$$G \quad (k;Z) = \frac{1}{Z + (Z)^{2d}(k) + \frac{G_{-1}(k;Z)}{G(k;Z)}t_{1} + \frac{G_{-+1}(k;Z)}{G(k;Z)}t_{+1}};$$
(8)

R +

and the latter equations can all be put into the form

$$\frac{G_{n+1}(k;Z)t_{n+1}n}{G_{n}(k;Z)} = Z + n(Z) \frac{2d_{n}(k)}{n(k)} + \frac{G_{n-1}(k;Z)t_{n-1}n}{G_{n}(k;Z)}$$

for n > 0, with a sim ilar result for the recurrence to the right. We de ne the left function

$$L_{n}(k;Z) = \frac{G_{n+1}(k;Z)t_{n+1}}{G_{n}(k;Z)}$$
(10)

and then determ ine the recurrence relation from Eq. (9)

$$L_{n}(k;Z) = Z + (Z)^{2d}_{n}(k) + \frac{t_{n}(z)^{2d}_{n}(k)}{L_{n}(k;Z)};$$
(11)

W e solve the recurrence relation by starting with the result for L $_1$, and then iterating Eq. (11) up to n = 1. O f course we do not actually go out in nitely far in our calculations. W e assume we have sem i-in nite metallic leads, hence we can determ ine L $_1$ by substituting L $_1$ into both the left and right hand sides of Eq. (11), which produces a quadratic equation for L $_1$ that is solved by

$$L_{1}(k;Z) = \frac{Z + \frac{1}{2}(Z) - \frac{2d}{1}(k)}{\frac{1}{2}q}$$
(12)
$$\frac{1}{2}q \frac{1}{[Z + \frac{1}{2}(Z) - \frac{2d}{1}(k)]^{2}} + \frac{2d}{1}(Z) - \frac{2d}{1}(k)^{2} - \frac{4d^{2}}{1} + \frac{1}{2}(Z) - \frac{2d}{1}(k)^{2} - \frac{2d}{1}(k)^{2}$$

The sign in Eq. (12) is chosen to yield an in aginary part less than zero for Z lying in the upper half plane, and vice versa for Z lying in the lower half plane. If L $_1$ is real, then we choose the root whose magnitude is larger than t $_1$ (the product of the roots equals t² $_1$). In our calculations, we assume that the left function is equal to the value L $_1$ found in the bulk, until we are within thirty planes of the root set of the root whose the we allow those thirty planes to be self-consistently determ ined with L possibly changing, and we include a sim ilar thirty planes on the right hand side of the last interface, term inating with the bulk result to the right as well.

In a similar fashion, we de ne a right function and a recurrence relation to the right, with the right function

$$m(k;Z) = \frac{G_{+n}(k;Z)t_{+n}+m_{+n}}{G_{+n}(k;Z)}$$
(13)

and the recurrence relation

$$R_{+n}(k;Z) = Z + {}_{+n}(Z) {}_{+n}^{2d}(k)$$
$$\frac{t_{+n+1}t_{+n+1+n}}{R_{+n+1}(k;Z)}; (14)$$

We solve the right recurrence relation by starting with the result for R_1 , and then iterating Eq. (14) up to n =1. As before, we determ ine R_1 by substituting R_1 into both the left and right hand sides of Eq. (14), which produces a quadratic equation for R_1 that is solved by

$$R_{1} (k;Z) = \frac{Z + \frac{1}{2} (Z) \frac{2^{d} (k)}{1}}{\frac{1}{2} (Z + \frac{2}{1} (Z) \frac{2^{d} (k)}{1} (k))^{2} 4t_{1}^{2}}$$
(15)

The sign in Eq. (15) is chosen the same way as for Eq. (12). In our calculations, we also assume that the right function is equal to the value R_1 found in the bulk, until we are within thirty planes of the rst interface. Then we allow those thirty planes to be self-consistently determined with R possibly changing, and we include a similar thirty planes on the left hand side of the last interface, term inating with the bulk result to the left as well.

U sing the right and left functions, we $% \mathcal{G}$ nally obtain the G reen's function

$$G (k;Z) = \frac{1}{L (k;Z) + R (k;Z) [Z + (Z)^{2d}(k)]}$$
(16)

where we used Eqs. (11) and (14) in Eq. (8). The local G reen's function on each plane is then found by sum – m ing over the two-dimensionalm on enta, which can be replaced by an integral over the two-dimensional density of states $(D \cap S)$:

$$G (Z) = d^{2d 2d} (^{2d})G (^{2d};Z); (17)$$

with

$${}^{2d}({}^{2d}) = \frac{1}{2 {}^{2}t^{k}a^{2}}K 1 \frac{1}{1 {}^{\frac{(2d)^{2}}{(4t^{k})^{2}}}}; \quad (18)$$

and K (x) the complete elliptic integral of the rst kind. If t^k varies in the nanostructure, then changing variables to = ${}^{2d}=t^k$ in Eq. (17) produces

G (Z) =
$$\begin{bmatrix} Z & _{4} \\ _{4} d & \frac{1}{2 & ^{2}a^{2}}K & 1 & 1 & \frac{2}{16} \end{bmatrix}$$
 G (t^k ; Z);
(19)

so that we can take the variable to run from 4 to 4 for the integration on every plane, and we just need to introduce the corresponding t^k substitution (for ^{2d}) into the left and right recurrence relations. In the bulk lim it, where we use t = t, we nd that the localG reen's function found from Eqs. (17) and (16) reduce to the well-known expressions for the three-dimensionalG reen's functions on a simple cubic lattice³, with a hopping param eter t.

O noe we have the localG reen's function on each plane, we can perform the DMFT calculation to determ ine the local selfenergy on each $plane^{9,10}$. We start with D yson's equation, which de nes the elective medium for each plane

$$G_0^{-1}(Z) = G^{-1}(Z) + (Z):$$
 (20)

The local G reen's function for the th plane satis es

G (Z) = (1
$$w_1$$
) $\frac{1}{G_0^1(Z) + \frac{1}{2}U} + w_1\frac{1}{G_0^1(Z)} + \frac{1}{2}U$;
(21)

with w_1 equal to the average lling of the localized particles [note that this above form is slightly di erent from the usual notation¹⁰, because we have made the theory particle-hole symmetric by the choice of the interaction in Eq. (1), so that = 0 corresponds to half lling in the barrier region and in the ballistic metal leads]. Finally, the self energy is found from

$$(Z) = G_0^{-1}(Z) - G_0^{-1}(Z)$$
: (22)

The full dynamical mean eld theory algorithm can now be stated. We begin by (i) making a choice for the self energy on each plane. Next, we (ii) use the left and right recurrences in Eqs. (11) and (14) along with the bulk values found in Eqs. (12) and (15) and a choice for the number of self-consistently determ ined planes within the metal leads (which we choose to be 30 to the left and the right of the barrier interfaces) to calculate the localG reen's function at each plane in the self-consistent region from Eqs. (16) and (19). Once the localG reen's function is known for each plane, we then (iii) extract the e ective medium for each plane from Eq. (20), (iv) determ ine the new local G reen's function from Eq. (21), and (v) calculate the new self energy on each plane from Eq. (22). Then we iterate through steps (ii) { (v) until the calculations have converged.

For all of the calculations in this work, we will assume the hopping matrix is unchanged in the metallic leads and the barrier, so all t₁ and all t^k are equal to t, which we take as our energy unit. We also work at the particle-hole symmetric point of half lling for the conduction electrons and the localized electrons. This yields w₁ = 1=2 and = 0.

There are a number of num erical details that need to be discussed in these computations. First, one should note that the recurrence relations in Eqs. (11) and (14) always preserve the imaginary part of R or L during the recursion. Hence the recursion is stable when R or L is com plex. On the other hand, when they are real, we nd that the large root is stable. Since this is the physical root, the recursion relations are always stable. Second, the integrand can have a number of singularities in it. W hen we calculate the M atsubara G reen's functions, the only singularity com es from the logarithm ic singularity in the two-dimensional DOS.We remove that singularity from the integration by using a midpoint rectangular integration scheme for 0.5 < jj < 4, and we change the variables for the region jj < 0.5 from to $x^3 =$, which is nite as x ! 0, and which has a nite slope as x ! 0; this allows a m idpoint rectangular integration scheme for $jxj < (0:5)^{1=3}$ to accurately determine this second piece of the integral. W hen we calculate the real frequency G reen's functions, we have the logarithm ic singularity, but we also can have a square-root singularity at the th plane in the denom inator of the integrand when (!) = 0 and i! +Re (!) j= 2.Wede ne Im a = ! + Re (!) + 2 and b = ! +(!) 2. Re Then, if a < 4 orb > 4, the only singularity lies at = 0as before. W hen b < 4, but 4 < a < 4, then there is a singularity at = a; when a > 4, but 4 < b < 4, then there is a singularity at = b; and when 4 < a; b < 4, there are singularities at a and b. The singularities are easy to transform away by using sine and hyperbolic cosine substitutions like = ! +Re (!) 2 sin and (!) 2 cosh into the respective pieces of = ! + Re the integrands where a singularity lies. We simply determ ine where all possible singularities lie (for each plane), set up an appropriate grid for the variable that takes the di erent changes of integration variable into account, and compute the associated weight functions for the integrations, in order to perform the integration over the two-dimensionalDOS.Third, we nd that when the correlations in the barrier are strong enough that we are in the M ott insulator for the bulk m aterial, and the barrier is su ciently thick, then the self energy develops a sharp structure, where the real part goes through zero over a sm all range close to ! = 0, and the imaginary part picks up a large delta-function-like peak around ! = 0. In order to properly pick up this behavior in the selfconsistent solutions, we need to use a very ne integra-

tion grid (we used up to one m illion points for the calculations reported on here) to perform the integration over the two-dimensional DOS. Such a negrid is only needed for frequencies close to ! = 0, but one needs to have a ne enough frequency grid in ! to pick up the sharp peak behavior in the self energy (we use a step size of 0.001 when there is a sharp structure in the self energy). For ordinary ! points, we typically used an integration grid of 5000 points. Fourth, these equations are easy to parallelize on the real-frequency axis, because the calculations for each value of frequency are completely independent of one another, so we simply use a master-slave approach and send the calculations at di erent frequencies to each of the di erent slaves until all frequencies are calculated. This approach has an alm ost linear scale up in the parallelization speed.

In addition to these single-particle properties, we also are interested in transport along the z-axis (perpendicular to the multilayered planes). The resistance of the nanostructures can be calculated by a K ubo-based linear response form alism ¹¹ (i.e., a current-current correlation function). We begin with the current operator at the th plane

$$j_{z} = \frac{x}{j_{z}};$$

$$j_{z} = \frac{ieat}{\tilde{z}} \qquad X \qquad c_{i}^{y}c_{+1i} \qquad c_{+1i}^{y}c_{i} \qquad (23)$$

This operator sum s all of the current owing from the th plane to the + 1st plane.

The current-current correlation function is de ned to be

$$(i_1) = d e^{i_1} hT j_z^V () j_z (0) i_z;$$
 (24)

with i $_1$ = i T 21 the Bosonic M atsubara frequency and with the dc conductivity m atrix determ ined by the analytic continuation of Eq. (24) to the real frequency axis via

() =
$$\lim_{! 0} \operatorname{Re} \frac{i^{-1}}{2}$$
 (25)

Substituting Eq. (23) into Eq. (24), evaluating the contractions in terms of the single-particle G reen's functions, performing the integration over to convert to the M atsubara frequency representation, and performing a Fourier transform over the 2d-spatial coordinates, yields the following result after some straightforward algebra:

$$(i_{1}) = \frac{eat}{\sim} T^{2} X X^{*}$$

$$G_{+1+1}(k;i!_{m})G_{k}(k;i!_{m}+i_{1})$$

$$+ G_{+1}(k;i!_{m})G_{+1}(k;i!_{m}+i_{1})$$

$$+ G_{+1}(k;i!_{m})G_{+1}(k;i!_{m}+i_{1})$$

$$G_{k}(i!_{m})G_{+1+1}(k;i!_{m}+i_{1}) (26)$$

Now we need to perform the analytic continuation from the imaginary to the real frequency $axis^{12}$. This is done by rst converting the summations over the Matsubara frequencies into contour integrals that enclose all of the Matsubara frequencies and are multiplied by the Ferm i-D irac distribution function f(!) = 1 = [1 + exp(!)]whichhas a pole at each Matsubara frequency. Then the contours are deformed to go along lines parallel (but justabove or just below) the real axis, and the real axis $shifted by <math>i_1$. At this point we replace $f(! i_1)$ by f(!) and then analytically continue $i_1! + i0^+$. The algebra is once again straightforward but som ewhat tedious. The nal result is

$$() = \frac{1}{2} \frac{eat}{2} \int_{k}^{2} \frac{eat}{2}$$

The last step is to evaluate the dc conductivity matrix, which becomes

$$(0) = \frac{2e^{2}}{h}a^{2}t^{2} d^{2d}() d! \frac{df}{d!}$$

$$Im G_{+1}(;!)Im G_{+1}(;!)$$

$$+ Im G_{+1+1}(;!)Im G_{(;!)}$$

$$Im G_{+1+1}(;!)Im G_{(;!)}$$

$$+ Im G_{(;!)}Im G_{+1+1}(;!): (28)$$

The conductivity matrix has the dimensions $e^2=ha^2$, which is the inverse of the resistance unit, divided by two factors of length, and is the correct units for the conductivity matrix.

Since the conductivity m atrix is not as familiar as the scalar conductivity used for hom ogeneous problem s, we will brie y derive how one extracts the resistance of the nanostructure from the conductivity m atrix. The key element that we use is that the current density that ow s through each plane is conserved, because charge current can neither be created nor destroyed in our device. The continuity equation, then says that the current density through the th plane, I , is related to the electric ed, E , between the th and + 1st plane via

$$I = a$$
 (0) $E = I;$ (29)

where we set the current density on each plane equal to a constant value I. Inverting this relation to determ ine the electric eld gives

$$E = \frac{1}{a} \begin{bmatrix} 1 \\ 0 \end{bmatrix} I:$$
(30)

The voltage across the nanostructure is just the sum of the electric eld between each plane, multiplied by the interplane distance (we assume a constant dielectric constant throughout), so we can im mediately determ ine the resistance area product (speci c resistance) from 0 hm 's law

$$R_n a^2 = \frac{V}{I} = \begin{bmatrix} I & I \\ I & I \end{bmatrix}$$
 (0)] : (31)

O ne needs to pursue a sim ilar type of analysis to exam ine the therm altransport properties (therm opower and therm al resistance), but it is som ewhat more complicated, because the therm al current is not conserved from one plane to another plane, as is the charge current. We will present results for such a calculation elsewhere (at half lling, where we restrict ourselves in this paper, there is no therm opower by particle-hole symmetry).

The only m athem atical issue associated with this analysis is that we have assumed the conductivity m atrix is invertible. In general, this is not true when there is no scattering in the m etallic leads. In this case, we need to truncate the conductivity m atrix to consider only the block that covers all of the planes in the barrier and the

rst metallic plane to the left and to the right of the barrier. This matrix is always invertible, and allow s calculations to be performed easily (if we were to include a larger matrix, we nd that the resistance does not increase as we increase the number of planes within the m etallic leads that we include in the conductivity m atrix block that is inverted, at least until we run into precision issues for the calculations). Of course, if the metallic leads have scattering, there are no num erical issues associated with the matrix inversion (except when the matrix ism ade too large and the system has approached the bulk lim it, see below), but we need to decide how far down the m etallic leads we will perform the actual m easurem ent, since the voltage grow swith the thickness of the metallic leads included in the calculation (when there is scattering in the leads).

In order to calculate the dc conductivity matrix in Eq. (28), we need to evaluate the o -diagonal components of the G reen's functions. This is easy to do using the renorm alized perturbation expansion, and the right and left functions. We not two recurrence relations

$$G_{n}(;!) = \frac{G_{n+1}t_{n+1}n}{L_{n}(;!)}; \quad (32)$$

(de ned for n > 0) and

$$G_{+n}(;!) = \frac{G_{+n}t_{+n}t_{+n}}{R_{+n}(;!)}; \quad (33)$$

(also de ned for n > 0). The other o -diagonal G reen's functions are found from the sym m etry relations: G $_n$ = G $_n$ and G $_{+\,n}$ = G $_{+\,n}$.

The computation of the junction resistance for a given temperature is relatively simple to perform. First, one must calculate all of the local self energies for each plane, using the algorithm described above. Then, for each frequency !, one can calculate all of the G reen's functions that enter into the form ula for (0). It is best to evaluate the integral over ! form any di erent temperatures \at the same time" since the only thing that changes with temperature (when at half lling, where the chem ical potential is xed and does not vary with T) is the Ferm i factor derivative. Since evaluating at each frequency is independent of every other frequency, this algorithm is also \embarrassingly parallel".

O ne nalcomment is in order about the formalism for calculating the junction resistance. Namely, how does it relate to a Landauer approach to the resistance? In the Landauer approach² one does not calculate a conductivity matrix, but instead determines the transport directly by evaluating the G reen's function G where lies at the left interface and lies at the right interface. We believe one can show that these two approaches are completely equivalent if one uses the same self energies for the inhom ogeneous structure to calculate the G reen's functions that enter into the transport calculation. We will examine this relationship in a future publication.

In a hom ogeneous (bulk) noninteracting system, we nd that the G reen's functions satisfy

$$G_{n}(;!) = \frac{1}{\frac{1}{4t^{2}(!+)^{2}}}$$
(34)
$$\frac{1}{\frac{1+1}{2}} + \frac{1}{\frac{1+1}{2}} +$$

when lies within the band [j! + j < 2]. Note that Im G (;!) is not always negative when $\frac{6}{5}$. This occurs because we are using a mixed basis, and the imaginary part of the Green's function does not have a de nite sign in this basis. We can substitute these Green's functions into the expression for the conductivity matrix, to evaluate the result for the bulk. We nd the matrix has all of its matrix elements equal to each other, and they assume the value

$$(0) = \frac{e^2}{ha^2} \int_{-2}^{2} d^{-2d} () = 0.63 \frac{e^2}{ha^2}; \quad (35)$$

for the case of half lling = 0 (since every matrix element is the same, the conductivity matrix is not invertible, but the resistance can still be calculated). This result will lead to precisely the Sharvin contact resistance 13,14,15 when we convert the conductivity into a resistance (the resistivity of a ballistic m etal vanishes, but the resistance is nonzero).

III. SINGLE-PARTICLE PROPERTIES

We perform our calculations at half lling (= 0, $hc_i^y c_i i = 1=2$, and $w_1 = hw_i i = 1=2$). This has a num ber of advantages. First, because the chem ical potential is the same for the metallic leads and the barrier, there is no electrochem ical force that reorganizes the electrons to a screened dipole layer at each of the interfaces, instead the lling remains hom ogeneous throughout the system . Second, the chem ical potential is xed as a function of tem perature, so there is no need to perform in aginary-axis calculations to determ ine the chem ical potential as a function of tem perature. W e usually calculate the M atsubara G reen's functions anyway, to test the accuracy of the real-axis G reen's function, by com paring the M atsubara G reen's functions calculated directly with those calculated from the spectral form ula via the real-axis DOS (usually the accuracy is better than three decim al points for every M atsubara frequency). Third, we can perform calculations of the resistance at all tem peratures in parallel, because the chem ical potential does not vary with tem perature (recall, the DOS of the Falicov-K in ball m odel is tem perature independent for the DMFT solution¹⁶). Fourth, the particle-hole sym m etry of the DOS allow sus to have another check on the accuracy of the calculations because we do not invoke that symmetry in our calculations. Fifth, there is a metalinsulator transition (MIT) in the bulk Falicov-K in ball model on a cubic lattice when U 4:9t, so the solutions at half lling include the MIT. For these reasons, we nd this case to be the simplest one to consider in a rst approach to the inhom ogeneous m any-body problem .

W e also reduce the number of parameters in our calculations by assuming all of the hopping matrix elements are equal to t for nearest neighbors. This is by nomeans necessary, but it allows us to reduce the number of parameters that we vary in our calculations, which allows us to focus on the physical properties with fewer calculations. The hopping scale t is used as our energy scale. W e also include 30 self-consistent planes in the metallic leads to the left and to the right of our barrier, which is varied between 1 and 80 planes in our calculations.

The rst problem we investigate is the extrem e quantum lim it of having one atom ic plane in the barrier of our device. We tune the Falicov-K in ball interaction in the one barrier plane from U = 1 to U = 20, which goes from a dirty m etal to well into the M ott insulating regime. But the M ott insulating phase does not like being con ned to a single atom ic plane, and there is a m etallic proxim ity e ect, where the m etallic DOS leaks into the insulator DOS at low energies. The result is that we do not expect the single-plane barrier to be too resistive. This is easiest to see when we consider the local DOS within the barrier

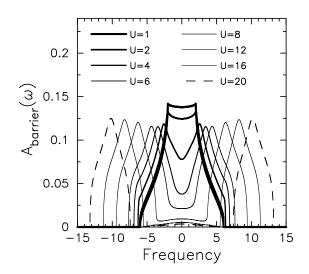
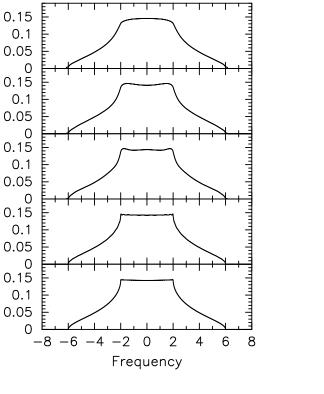


FIG.1: Barrier DOS as a function of the Falicov-K in ball interaction U. The di erent line widths and styles denote di erent U values, as detailed in the legend. Note how the DOS initially evolves as in the bulk, with the DOS being reduced near ! = 0, and the band width increasing. But as we pass through the M ott transition, we see that the doublepeak M ott-H ubbard bands appear, but so does a low -energy (interface-localized) band near ! = 0, which looks like a low weight m etallic band for large U.

plane, as plotted in Fig. 1. There we see that the DOS starts to be reduced at the chem ical potential as we in crease U, but there is still substantial DOS at the Ferm i energy when U 4:9. In fact, as U is increased, we see that the upper and lower M ott-H ubbard bands form, centered at U=2, but there is signi cant DOS that remains centered at ! = 0, and it even develops a small peak for U > 10. The origin of, and the size of this peak, can be shown to arise naturally from the renorm alized perturbation theory expressions for the G reen's functions, but we do not do so here¹⁷. We anticipate that these states are localized at the interface, and represent the states that an incident electron can tunnel through to go from one metallic lead to the other in a transport experiment. These results show a number of interesting features of the coupling of a M ott insulator to a m etallic lead: (i) the M ott transition remains in the sense that M ott-H ubbard bands continue to form, with their origin clearly seen near the M II; (ii) the interface-localized states have a m etallic character (i.e., a peak at ! = 0) in the large-U regime; and (iii) the proximity e ect appears to always be active, and able to create states within the barrier at low energy, but the total weight in those states is low, so medium to high energy properties of the M ott insulator phase will rem ain sim ilar to the bulk.

Next we exam ine what happens as we increase the barrier thickness for given values of U. Our focus is on three generic values of interest: U = 2, which is a strongly scattering, di usive m etal; U = 4, which is so close to the M IT, that the bulk DOS show a signi cant



 $A_{-1}(\omega)$

 $A_{-2}(\omega)$

 $A_{-3}(\omega)$

 $A_{-30}(\omega) A_{-10}(\omega)$

FIG.2: Lead DOS for an N = 5 barrier device with U = 2. The di erent panels show the DOS in the rst metal plane to the left of the barrier, in the second, the third, the tenth and the thirtieth. Note how the system approaches the bulk cubic DOS as it moves further from the interface, as expected. A careful examination of the panels shows that the $\$ at" region with j! j < 2 shows a half-period oscillation for each unit of distance from the current plane to the interface, but the am plitude shrinks dram atically as we move further from the interface.

dip near ! = 0; and U = 6, which is well within the Mott-insulating phase. We rst exam ine how the metallic leads are in uenced by the presence of the barrier. We set the origin of the variables so that = 0 corresponds to the rst barrier plane (hence planes 1 to 30 represent the thirty planes to the left of the barrier, with 1 closest to the barrier). In Fig. 2, we show results for U = 2 and ve representative planes in the metal (the device has ve barrier planes). In Fig. 3, we show the same results for U = 4 and in Fig. 4, we show the same results for U = 6. The rst thing to notice is that the DOS is close to that of the bulk simple cubic lattice for 30 planes away from the interface, indicating that our choice of thirty self-consistent planes is reasonable. Next, note that the amplitude of the oscillations grows as U increases. Third, the number of half periods in the oscillations increases with the distance away from the interface (both for j! j < 2 and j! j > 2). The source of these oscillations is the Friedeloscillations (with a wavelength on the order of two lattice spacings for half lling) that we expect associated with the disturbance

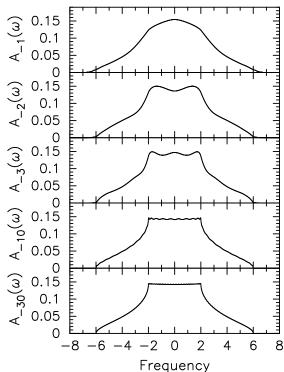


FIG.3: Lead DOS for an N = 5 barrier device with U = 4. The di erent panels show the DOS in the rst metal plane to the left of the barrier, in the second, the third, the tenth and the thirtieth. Note how the am plitude of the oscillations increases as U increases.

of the Ferm i sea of the metal by the proximity to the interface.

There are two interesting questions to ask about these results: how thick does the barrier have to be before the Friedel oscillations become frozen in the metallic leads and don't change with a thicker barrier, and do we see oscillatory behavior in the barrier, where we instead expect there to be exponentially decaying wavefunctions? We nd that the answer to the rst question is that the structure is already essentially frozen in for a single-plane barrier, and it does not evolve much with the barrier thickness (although it does show much evolution with the interaction strength). This perhaps sheds som e light on why non-self-consistent Landauer based approaches for transport have been so successful. If one has a good guess for the sem i-in nite lead DOS, then it does not change much as the thickness increases, so that guess will work well for all calculations with the same strength of electron correlations.

To exam ine the second question, we plot results for the DOS at a xed frequency (four chosen for each U value) in Fig. 5. There are six di erent thicknesses plotted for each U value. The curves all lie on top of each other for the metallic lead planes, indicating that the Friedel oscillation structure is frozen in starting at N = 1 (and we can read o the oscillation wavelength to be two lat-

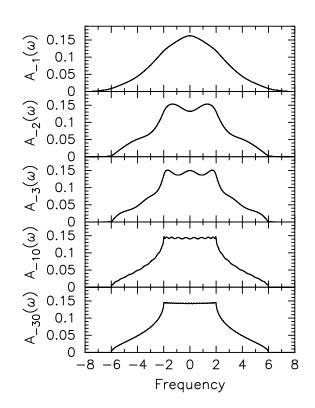


FIG.4: Lead DOS for an N = 5 barrier device with U = 6. The di erent panels show the DOS in the rst m etal plane to the left of the barrier, in the second, the third, the tenth and the thirtieth. Note how the am plitude of the oscillations is even larger here. A careful exam ination shows there are also oscillations (with the same kind of increase in the num ber of halfperiods with the distance from the interface) in the region j! j > 2.

tice spacings, with a sharp decrease of the amplitude as one moves away from the interface). In the barrier, we see that there are only oscillations close to the interface, then the curves either atten out or exponentially decay with thickness. But the curves continue to lie on top of each other (except for the middle plane of the barrier for sm all ! and U = 6). These results, once again, show that another of the assumptions of the non-self-consistent Landauer-based approaches, that there is an exponential decay with a well de ned decay length in the insulating barrier regions, holds here as well, but one needs to properly predict the decay length to perform accurate calculations.

O ur nalsum mary of the DOS is included in false color plots (the color, or grayscale, denoting the height of the DOS at a given plane) to emphasize the spatial location and am plitudes in the oscillations. Fig. 6 shows the results for N = 1 and U = 6 and Fig. 7 shows the results with N = 20 and U = 6 (only half of the nanostructure planes are shown due to the mirror symm etry). The color scale (or grayscale) needs to use a banded rainbow, with the di erent colors (grayscales) separated by bands of black in order to pick up the sm all am plitude oscilla-

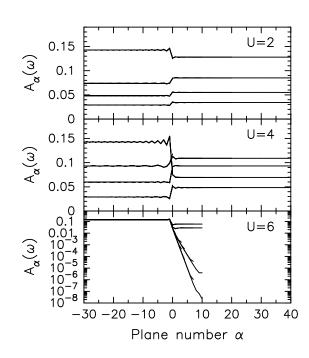


FIG.5: DOS at specic values of ! as a function of the plane position in the device. W e plot only the left-hand piece of the plots, since the right-hand piece is a m irror in age of the lefthand piece. Note that the U = 6 panel is a sem ilogarithm ic plot. The four values of ! for U = 2 are 0.0, 3.0, 4.0, and 5.0. The barrier thicknesses are N = 1, 5, 10, 20, 40, and80. The four values of ! for U = 4 are 0.0, 2.5, 3.5, and 5.0. The barrier thicknesses are N = 1, 5, 10, 20, 40, and 80. The four values of ! for U = 6 are 0.0, 0.2, 0.4, and 1.0. The thicknesses are N = 1, 4, 7, 10, 15, and 20. Note how all curves lie on top of each other in the m etallic lead, indicating the structure in the metallic lead is frozen in for an N = 1barrier, and does not signi cantly change with increasing ${\tt N}$. In the barrier, we only have oscillations at the interface, and then the curves either are at with thickness (U = 2 and 4), or exponentially decreasing or at (U = 6). The little tails that stick out for the low est two frequencies with U = 6 show that the middle plane of the barrier does not follow the same exponential decay as the other planes do. But the exponent of the exponential decay is frozen in starting at N 1.

tions in the background of the large DOS.Note how the Friedel oscillations are essentially the same in the two plots, indicating this freezing of the oscillations starting at N = 1. There are also oscillations visible near the m etalband edges, indicating Friedel-like oscillations due to the di erent total bandwidths of the two m aterials joined in the nanostructure. The DOS in the barrier at low frequency becomes very small very quickly on these linear scales, but it is nonzero (see Fig.5).

The nal single-particle property we consider is the imaginary part of the self energy at the central plane of the barrier at low energy in Fig.8. In the bulk, the imaginary part of the self energy vanishes within the M ott-Hubbard gap, except for a delta function at ! = 0 whose weight can be used as a quasi-order parameter for the M ott transition at half lling (but not away from half

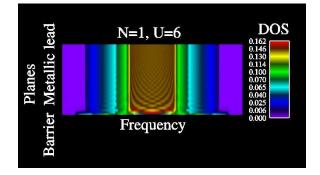


FIG.6: False-colorplot of the DOS for a N = 1 barrier plane device with U = 6. The barrier plane is just the lowest plane at the bottom of the gure, while the thirty metallic planes lie on top. Note how the ripples of the Friedel oscillations are most visible in the central region, where the DOS has a plateau. (Color version on line.)

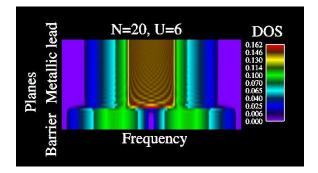


FIG. 7: False-color plot of the DOS for a N = 20 barrier plane device with U = 6. The barrier planes are the lower ten planes, while the thirty m etallic planes lie on top. Note how the ripples of the Friedel oscillations agree with those in Fig. 6. In the barrier, the DOS decreases rapidly on this linear scale, and shows few oscillations, but one can see som e sm all oscillations near the band edges in both regions. (C olor version online.)

 $lling^{18}$). In the nanostructures, the imaginary part of the self energy never vanishes in the bulk gap region, but it can assume very small values, with a sharp peak, of nite width, developing at ! = 0. This peak grows in height and narrows as the barrier is made thicker. It is a challenge to try to calculate such a structure num erically, especially due to the loss of precision in extracting the self energy from the D yson equation during the iterative algorithm. It requires a neenough frequency grid to pick up the narrow structure, and it requires a su ciently ne integration grid for , in order to accurately determ ine the peak value. Note how the self energy evolves from a relatively broad featureless structure to a very sharply peaked structure as the barrier is made thicker. This kind of a peaked self energy is similar to what is seen in the exact solution on the hypercubic lattice in innite dimensions. There the Mott transition is actually to a pseudogap phase, with the DOS vanishing only at the chem ical potential, but there is a region of exponen-

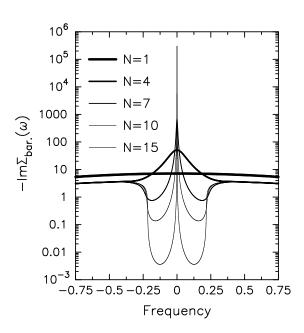


FIG.8: Sem ilogarithm ic plot of the imaginary part of the self energy on the central plane of the barrier at sm all frequency for ve di erent thickness barriers (N = 1, 4, 7, 10, and 15). Note how the imaginary part of the self energy becomes very sm all for frequencies close to ! = 0, but as we approach ! = 0, a sharp delta-function-like peak develops that narrows as the barrier is made thicker. It is precisely this structure that is hard to reproduce with num erical calculations. Note that this kind of a self energy is very sim ilar to what is seen in the hypercubic lattice in in nite dimensions.

tially smallDOS in the \gap region". The sharp features in the selfenergy led to a signi cant enhancement of the low-tem perature them opower on the hypercubic lattice, when the system was doped o of half lling¹⁹ (and w₁ changed to produce an insulator). It is unclear at this point whether such behavior could lead to enhancements in the nanostructures, even though the self energy has sim ilar properties.

IV. GENERALIZED THOULESS ENERGY

It is important to try to bring sem iclassical ideas of transport into transport in nanostructures, to see whether those concepts have useful quantum analogues. Thouless was the rst to investigate such ideas for diusive m etal barriers^{4,5}. He considered the idea of a dwell time in the barrier for an electron that tries to travel through the barrier. If we assume the electron takes a random walk through the barrier, then the time it spends inside the barrier is proportional to the square of the thickness of the barrier (with the proportionality being related to the di usion constant). Since one can extract the di usion constant, via an E instein relation, from the junction resistance, T houless could construct a quantum – m echanical energy ~=t_{dw ell} from these classical ideas. It

turns out that this energy scale plays a signi cant role in determining the quantum dynamics of many di erent kinds of nanostructures. For example, it can be easily generalized to take into account ballistic m etals, where $t_{dw\,ell} = N a = v_F$ for a barrier of thickness N a, with v_F the Ferm i velocity. The Thouless energy appears to be the critical quantum energy scale that determines the dynamics through weakly correlated nanostructures; its success in the theory of Josephson junctions is particularly notew orthy⁶.

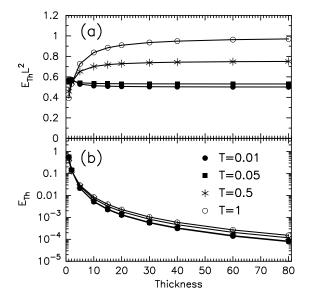


FIG. 9: Thouless energy for a U = 4 (di usive, but very strongly scattering m etal) barrier as a function of the barrier thickness L = N a. The di erent curves correspond to different tem peratures. The top panel multiplies the Thouless energy by L^2 to try to isolate the prefactor for the di usive transport, while the bottom panel plots the Thouless energy on a sem i-logarithm ic plot. Note that the tem perature dependence of the constant, seen for thick barriers in panel (a), arises from the fact that the U = 4 DOS has signi cant low – energy structure, because there is a dip that develops near the chem ical potential, so the tem perature dependence is both stronger than expected for norm alm etals, and anom alous because m any m ore states are involved as T is increased, i.e. it behaves m ore like an insulator.

So the fundam ental question we wish to investigate is can the concept of a Thouless energy be generalized to a strongly correlated system, where transport through a nanostructure is either via tunneling or via incoherent them al excitation. The answer is yes, and we do so by rst trying to extract an energy scale from the resistance of the junction, which is able to track the putative therm aldependence of the resistance when we are in the incoherent therm al transport regime. A simple dimensionality argument shows that the form

$$E_{Th} = \frac{R}{R_{n}a^{2}2e^{2}} \frac{R}{d!} [df=d!]_{bulk} (!) Na$$
(36)

has the kind of dependence we are looking for. The

symbol bulk (!) is the localDOS in the bulk for the material that sits in the barrier of the nanostructure. If we check the dimensions, we see that R_n has dimensions $h=e^2$, and the DOS has dimensions $1=a^3t$, so E_{Th} is an energy [note Eq. (36) corrects typos in an earlier work 7]. W hen we exam ine system s where the barrier is a m etal, then at low tem perature the bulk DOS can be replaced by a constant in the integral, and we reproduce the known C≓N a) form s for the Thouless energy for ballistic (E_{Th} $C^{0} = [N a]^{2}$) electrons because the reand di usive (E_{Th} sistance is independent of the thickness for a ballistic m etal barrier and it grows linearly with the thickness for a di usive m etalbarrier. This m ethod of generalizing the Thouless energy also avoids us having to try to answer the question of how long does it take an electron to tunnel from the left to the right lead, and it reproduces all of the known form s for the Thouless energy in a unifying form ula that does not require us to even use the E instein relation to extract a di usion constant or to determ ine the Fermi velocity for an anisotropic Fermi surface (in the ballistic case).

W e plot the results for this T houless energy as a function of thickness in Fig. 9 for U = 4. In panel (a), we $multiply E_{Th}$ by the square of the length L = N a of the barrier. The di erent curves correspond to di erent tem peratures. If the Thouless energy went exactly like $C^{0}=L^{2}$, then all of the curves would be straight lines, with a tem perature-dependent value $C^{0}(T)$. But we see som e curvature for sm all barrier thicknesses. This arises mainly from the fact that in addition to the di usive contribution to the resistance, there is a contact resistance, so for thin barriers, we do not have a pure $1=L^2$ behavior. Note, however, that the Thouless energy has little tem perature dependence at low tem perature, as expected. In panel (b), we plot the curves on a sem i-logarithm ic plot, so one can see how small the Thouless energy becomes for thicker junctions.

The Thouless energy is plotted versus tem perature on a log-log plot for U = 6, which corresponds to a M ottinsulating barrier with a small correlation-induced gap. The dashed line indicates where $E_{Th} = T$, which is an im portant crossover point for dynam ics, as we will see below. Note that the temperature dependence is signi cant in an insulator, because the integral in the denom inator of Eq. (36) has strong tem perature dependence in the insulator, but the resistance does not in the tunneling regime at low temperature. If we used the Thouless energy to determ ine the tunneling time via $t_{tunnel} = \sim = E_{Th}$, we would not tunneling times rapidly approaching zero as T ! 0.W e will not com m ent further here as to whether there is any substance to using such results to describe the quantum dynam ics of the tunneling process. Instead we simply want to conclude that the concept of the Thouless energy can be generalized to strongly correlated systems, and we will see below that the crossover point where E_{Th} T has in portant physical interpretations that will be developed in the next section. Finally, the generalization of the Thouless energy

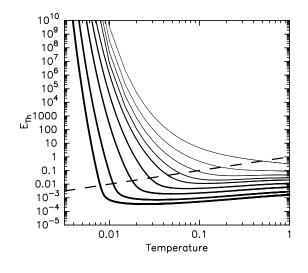


FIG.10: Thouless energy for a U = 6 (M ott-insulating) barrier as a function of temperature on a log-log plot. The di erent curves correspond to di erent thicknesses of the barrier, ranging from N = 1 for the top curve to N = 2, 3, 4, 5, 7, 10, 15, and 20 as we move down the plot. Note how the Thouless energy picks up dram atic temperature dependence here. The dashed line is the curve where $E_{Th} = T \cdot W$ e nd that when the Thouless energy equals the temperature, interesting e ects occur (see below).

to correlated system s changes the idea of a single energy scale being associated with the transport, since now the energy scale develops strong tem perature dependence. If a single num ber is desired, then we would propose to use the energy scale where the Thouless energy is equal to the tem perature, indicated by the points of intersection of the solid lines with the dashed curves in Fig.10.

V. CHARGE TRANSPORT

The dc resistance is a low energy property of the nanostructure, and so it requires the results of the singleparticle properties to be determ ined accurately at low energy. This is not di cult form etallic barriers with any degree of scattering, as long as the num erical subtleties discussed above are taken into account in the analysis, but it does create problem s for thick M ott insulators. W e need to be able to properly determ ine the structure seen in F ig. 8 as the barrier is m ade thicker, and this can exhaust the num erical resources, or the num erical precision available for a given calculation. For our work, we were not successful in exam ining U = 6 barriers thicker than N = 20.

We plot the resistance-area product in Fig. 11 for T = 0.01 and four di erent U values: U = 2, a di usive m etal near the Io e-Regel lim it of a mean free path on the order of a lattice spacing; U = 4, a strongly scattering, anom alous m etal, that has a strong dip in the DOS near the chem ical potential; U = 5, a M ott-insulator

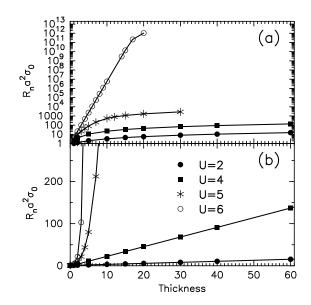


FIG.11: Resistance-area product for nanostructures with U = 2, 4, 5, and 6, and various thicknesses. Panel (a) is a sem i-logarithm ic plot, while panel (b) is a linear plot. The tem perature is T = 0.01 in both panels. Note how the correlated insulator (U = 6) has an exponential growth with thickness as expected for a tunneling process, but it turns over at the thickest junction, indicating a crossover to the incoherent transport regime. The U = 5 data, which is close to the critical point for a M IT, has neither linear, nor exponential growth of its resistance-area product. The m etallic cases (U = 2 and 4) have perfect linear scaling of the resistance with current, with a nonzero intercept corresponding to the contact resistance. This may be surprising for U = 4, because it is so strongly scattering (with a mean free path much less than a lattice spacing), that one would not think a sem iclassical approach should apply there. The constant satis es $_{0} = 2e^{2} = ha^{2}$.

that is nearly critical; and U = 6, a M ott-insulator with a sm all correlation-induced gap. In panel (a), we have a sem i-logarithm ic plot, which is useful for picking out tunneling behavior via an exponential increase of the resistance with thickness. This is clearly seen for the M ott insulator with U = 6, with the beginnings of a crossover occurring near N = 20, but the near-critical insulator at U = 5 does not grow exponentially, nor does it grow linearly [see panel (b)]. The data for U = 2 and U = 4, both show linear increases with thickness, with a nonzero intercept on the y-axis denoting the nonzero contact resistance with the m etallic leads. It is suprising that this linear $\langle 0 \ \text{hm ic}'' \ \text{scaling holds for system s that are so$ strongly scattering, that their m ean free path is muchless than one lattice spacing.

Our nal gure plots the resistance-area versus tem – perature for (a) U = 4 and (b) U = 6 [Fig. 12]. In panel (a), we can infer a linear dependence of $R_n a^2$ versus L for all tem peratures, so this barrier is always 0 hm ic in nature. But it has quite anom alous tem perature dependence, looking like an insulator, whose resistance is

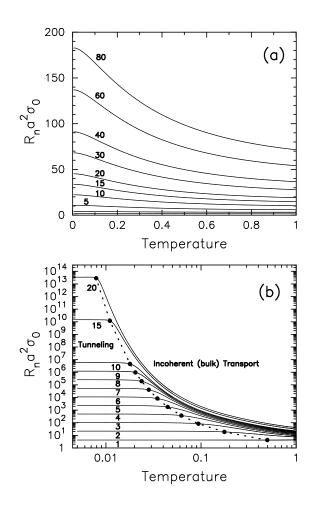


FIG.12: Resistance-area product for nanostructures with (a) U = 4 and (b) U = 6 as a function of tem perature [panel (a) is on a linear scale, and panel (b) is a log-log plot]. In panel (a) we include results for N = 1, 2, (lowest two curves), 5, 10, 15, 20, 40, 60, and 80. Note how at each temperature there is a linear dependence of the resistance-area product with the thickness of the junction. Note further, that these junctions have anom alous tem perature dependence for a m etal (they actually look insulating in their dependence). In panel (b), we show the results for U = 6 with N = 1 10, 15 and 20. Note at low tem perature we have tunneling, as the resistance-area product is weakly dependent on tem perature, and the steps are equally spaced as a function of thickness, indicating exponential dependence on the thickness. At higher tem peratures, there is a crossover to the incoherent transport regime, with the resistance-area product picking up a strong T dependence, and scaling linearly with the thickness. The dotted line that connects the solid dots is a plot of the resistance-area value at the tem perature where $E_{Th} = T$ which determ ines the crossover.

reduced as the tem perature increases. In panel (b), we see an exponential dependence of $R_n a^2$ versus L at low tem perature, m arked by the equidistant step increases of $R_n a^2$ as the thickness increases (recall this is a log-log plot). The tem perature dependence is also weak in this region, indicated by the atness of the curves. Hence the

system is in the tunneling regime at low temperature. As T rises, there is a relatively sharp crossover region, where $R_n a^2$ begins to pick up strong (exponentially activated) T dependence, and $R_n a^2$ grows linearly with L. This is the incoherent \0 hm ic" regime for the transport. The solid dots represent the resistance-area product at the Thouless energy, determ ined by nding the tem perature where $E_{Th} = T$ from Fig. 10, and marking those points on the curves in panel (b). A dashed line quide to the eye is drawn through these points. One can clearly see that the point where the Thouless energy equals the tem perature determ ines the crossover from tunneling to incoherent transport. Surprisingly, this crossover occurs at a low ertem perature for a thicker barrier. This occurs, because the tunneling resistance is higher for a thicker barrier. As T increases, the Ohm ic resistance, determined by multiplying the temperature-dependent bulk resistivity by the thickness and dividing by the area, will decrease. Once it is essentially equal to the tunneling resistance, there will be a crossover from tunneling, which provides a \quantum short" across the junction for low T, to \0 hm ic" (incoherent) therm ally activated transport. This must occur at a lower tem perature for more resistive junctions, and hence the thicker junctions have the crossover before the thinner junctions. Note that the tem perature scale for this crossover does not appear to have any simple relation to the energy gap of the bulk m aterial, instead it is intim ately related to the dynam ical information encoded in the generalized E_{Th} found in Eq.(36).

W e do not consider them al transport there, since the therm opower vanishes for this particle-hole symmetric case and the therm al resistance is not as interesting in system s with vanishing therm opower.

VI. CONCLUSIONS

In this contribution we worked with a generalization of DMFT to inhom ogeneous systems to calculate the selfconsistent m any-body solutions for multilayered nanostructures that have barriers that can be tuned to go through the M ott transition. W e developed the com putational form alism thoroughly (based on the algorithm of Pottho and Nolting), and although we applied it only to the Falicov-K in ballm odel, it is obvious that one can trivially add m ean-eld-like interactions such as Zeem an splitting for magnetic systems, or long-range Coulomb interactions for systems with m ism atched chem ical potentials. In addition, one can invoke whatever in purity solver desired for the local DMFT problem on each plane, which extracts a new self energy from the current local Green's function. We studied both the single-particle properties and the charge transport.

There are a number of interesting results that came out of this analysis. First, we found that as the strength of the correlations increases in the barrier, there is a stronger feedback e ect on the Friedel-like oscillations

that appear in the metallic leads, but those oscillations vary little with the thickness of the barrier for a xed interaction strength. Second, there are few oscillations inside the barrier except close to the interface with the m etallic leads, but the behavior in the barrier, of either an exponential decay, or of a constant DOS, gets frozen in for a relatively thin barrier, and the DOS changes litthe with increasing the thickness of the barrier, except when there is exponential decay which will always decrease within the correlation-induced gap. Third, the M ott insulating barrier develops a narrow peak-like structure in the imaginary part of the self energy that approaches the bulk delta function result. This narrow and tall peak is di cult to determ ine accurately with the numerics and limits the ability to study thick insulating barriers. Fourth, we showed how to generalize the concept of a Thouless energy to become a function of T for a strongly correlated M ott insulator. O ur unifying form for the Thouless energy includes the results for both the ballistic and di usive m etals as well. W e identi ed an energy scale that describes the crossover from tunneling to incoherent transport in these nanostructures; it corresponds to $E_{Th} = T$. This energy scale is quite useful in other areas such as in the theory of Josephson junctions, which will be presented elsew here. Sixth, we analyzed the resistance of these devices and found interesting behavior, including anom alous m etallic behavior (but no tunneling) for a strongly scattering metal, and the crossover from tunneling to 0 hm ic transport for insulating barriers.

This work also shed light on other approaches to transport through multilayered structures like the Landauerbased approaches. U sually these are non-self-consistent techniques that approach the problem from the point of view of transmission and relection of Bloch wavesmoving through the device. W e found that because the structure in the leads is frozen in beginning with N = 1 and because the exponential decay lengths are also determ ined from N = 1, if one knew those results and plugged them into the Landauer approach, one should be able to calculate accurate properties; i.e. the self consistency is needed for each nanostructure, but the self-consistency hardly changes with the thickness of the barrier. Hence a phenom enological approach that adjusts the properties of the barrier height to produce the required behavior, m ay work well, even for strongly correlated system s; of course, the many-body theory is the only way to determ ine the precise structure needed via its self-consistent

solution (i.e. it requires no thing).

There are a number of important e ects that we have not discussed here, which play roles in the transport through nanostructures. W e did not attempt to include them in this rst, simplest problem that we tack led. The rst one is the issue of charge reorganization around the interface. If the chem ical potentials of the leads and the barriers are di erent, electrons will spill from one plane to the another until a screened dipole layer is form ed, and a constant electrochem ical potential is found throughout the device²⁰. Such e ects can have dram atic results if one or more of the materials is a correlated insulator, since the inhom openeous doping of the system can transform part of it from insulating to metallic. This is believed to occur in grain boundaries in high temperature superconducting tapes and wires²¹, and in insulator-based nanostructures^{22,23}. Second, calculations should be perform ed o of half lling, where the therm al evolution of the chem ical potential, will likely undergo som e tem perature dependence so the charge rearrangem ent can vary with tem perature in the system . Third, we should calculate the therm al transport e ects. Since these calculations require particle-hole asymmetry, we will have the chem ical potential evolution and the charge reorganizations to deal with as well. Fourth, one can include ordered phase e ects at the mean-eld level easily, as in a superconductor for a Josephson junction²⁴, or in a ferrom agnet for a spintronics device. Fifth, it will be useful to determ ine the capacitance of a nanostructure, since the capacitance is often important in determining the switching speed of a device; it can be calculated with a linear-response form alism as well. Finally, we also should look into nonequilibrium e ects, especially the nonlinear response of a current-voltage curve. It is our plan to investigate these com plications in the future.

A cknow ledgm ents

W e would like to thank V. Z latic for useful discussions. W e acknow ledge support from the N ational Science Foundation under grant num ber D M R-0210717 and the O ce of N avalR esearch under grant num ber N 00014-99-1-0328. Supercom puter tim e was provided by the A rctic R egion Supercom puter C enter and by the M ississippi R egion Supercom puter C enter ERD C.

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